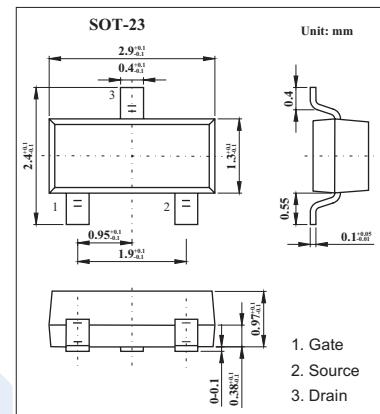
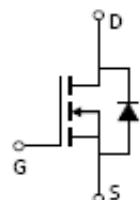


**N-Channel Enhancement Mode  
Field Effect Transistor  
KO3402(AO3402)**

■ Features

- $V_{DS}$  (V) = 30V
- $I_D$  = 4 A
- $R_{DS(ON)} < 55m\Omega$  ( $V_{GS} = 10V$ )
- $R_{DS(ON)} < 70m\Omega$  ( $V_{GS} = 4.5V$ )
- $R_{DS(ON)} < 110m\Omega$  ( $V_{GS} = 2.5V$ )



■ Absolute Maximum Ratings  $T_a = 25^\circ C$

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	$V_{DS}$	30	V
Gate-Source Voltage	$V_{GS}$	$\pm 12$	V
Continuous Drain Current $TA=25^\circ C$	$I_D$	4	A
$TA=70^\circ C$		3.4	
Pulsed Drain Current	$I_{DM}$	15	
Power Dissipation $TA=25^\circ C$	$P_D$	1.4	W
$TA=70^\circ C$		1	
Thermal Resistance.Junction-to-Ambient	$R_{\theta JA}$	125	$^\circ C/W$
Thermal Resistance.Junction-to-Case	$R_{\theta JC}$	80	$^\circ C/W$
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	$^\circ C$

**KO3402(AO3402)**

■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Testconditons	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	V <sub>DSS</sub>	I <sub>D</sub> =250 μ A, V <sub>GS</sub> =0V	30			V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>D</sub> =24V, V <sub>GS</sub> =0V			1	
		V <sub>D</sub> =24V, V <sub>GS</sub> =0V, T <sub>J</sub> =55°C			5	μ A
Gate-Body leakage current	I <sub>GSS</sub>	V <sub>D</sub> =0V, V <sub>GS</sub> =±12V			±100	nA
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>D</sub> =V <sub>GS</sub> I <sub>D</sub> =250 μ A	0.6	1	1.4	V
Static Drain-Source On-Resistance	R <sub>D(on)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =4A		45	55	mΩ
		V <sub>GS</sub> =10V, I <sub>D</sub> =4A T <sub>J</sub> =125°C		66	80	
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =3A		55	70	mΩ
		V <sub>GS</sub> =2.5V, I <sub>D</sub> =2A		83	110	mΩ
On state drain current	I <sub>D(on)</sub>	V <sub>GS</sub> =4.5V, V <sub>D</sub> =5V	10			A
Forward Transconductance	g <sub>FS</sub>	V <sub>D</sub> =5V, I <sub>D</sub> =4A		8		S
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> =0V, V <sub>D</sub> =15V, f=1MHz		390		pF
Output Capacitance	C <sub>oss</sub>			54.5		pF
Reverse Transfer Capacitance	C <sub>rss</sub>			41		pF
Gate resistance	R <sub>g</sub>	V <sub>GS</sub> =0V, V <sub>D</sub> =0V, f=1MHz		3		Ω
Total Gate Charge	Q <sub>g</sub>	V <sub>GS</sub> =4.5V, V <sub>D</sub> =15V, I <sub>D</sub> =-4A		4.34		nC
Gate Source Charge	Q <sub>gs</sub>			0.6		nC
Gate Drain Charge	Q <sub>gd</sub>			1.38		nC
Turn-On DelayTime	t <sub>D(on)</sub>			3.3		ns
Turn-On Rise Time	t <sub>r</sub>	V <sub>GS</sub> =10V, V <sub>D</sub> =15V, R <sub>L</sub> =3.75 Ω, R <sub>GEN</sub> =6 Ω		1		ns
Turn-Off DelayTime	t <sub>D(off)</sub>			21.7		ns
Turn-Off Fall Time	t <sub>f</sub>			2.1		ns
Body Diode Reverse Recovery Time	t <sub>rr</sub>			12		ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>F</sub> =4A, dI/dt=100A/ μ s		6.3		nC
Maximum Body-Diode Continuous Current	I <sub>s</sub>				2.5	A
Diode Forward Voltage	V <sub>SD</sub>	I <sub>s</sub> =1A, V <sub>GS</sub> =0V		0.8	1	V